



| | | |
|---|--|---------------------------------------|
| Title of Change: | Adding King Yuan Electronics Corp Taiwan (KYECC) as an additional Final Test Location | |
| Proposed first ship date: | 15 October 2015 or Earlier upon customer approval. | |
| Contact information: | Contact your local ON Semiconductor Sales Office or Tamara Olney <Tamara.Olney@onsemi.com> | |
| Samples: | Contact your local ON Semiconductor Sales Office. | |
| Type of notification: | <p>This is an Initial Product/Process Change Notification (IPCN) sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.</p> <p>The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact <PCN.Support@onsemi.com>.</p> | |
| Change category(s): | <input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Material Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____ | |
| Sites Affected: | Site 1 | Site 2 |
| <input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input type="checkbox"/> ON Semiconductor site(s) : <input checked="" type="checkbox"/> External Foundry/Subcon site(s): | | King Yuan Electronics Co., Ltd. |
| Description and Purpose: | | |
| Adding KYECC as an additional test site to increase ON Semiconductor test capacity. This change does not affect the product form, fit, or function. KYECC is a qualified test house for ON Semiconductor. | | |
| Qualification Plan: | | |
| Estimated date for qualification completion: 3 July 2015 | | |
| Qualification will be per ON Semiconductor 12MID07-0107. This includes repeatability tests, correlation of parametric measurements, and yield/bin correlation. | | |
| Full parametric correlation will be performed and for every test the shift will be evaluated as follows: | | |
| dmean = abs(mean(ref)-mean(qual)) | | |
| dsigma = 0 | | if sigma(qual) < sigma(ref) |
| dsigma = sigma(qual) – sigma(ref) | | if sigma(qual) > sigma(ref) |
| shift = dmean + 4 * dsigma | | |
| If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test, | | else correlation is NOK for this test |
| <i>Any parameter that exceeds the allowable shift is independently analysed and explained</i> | | |



List of Affected Standard Parts:

NCP1090DRG
NCP1090DG
SCY4001DG
NCN5120MNTWG
AMIS30543C5431RG
NCP1092DG
NCP1092DRG
NCN5193MNTWG
NCS37013MNTWG
NCS37010DBRG

NOTE: Please be informed that parts impacted by this PDN/PCN are Special/Customer specific parts, thus MPN & CPN info will be available to affected customers only by clicking the "[Custom PCN for Selected Company Button](#)" in the Document Analysis page of PCMS/PCN Alert.